

Evaluation of Mixed-Signal Noise Effects in Photon Counting X-Ray Image Sensor Readout Circuits

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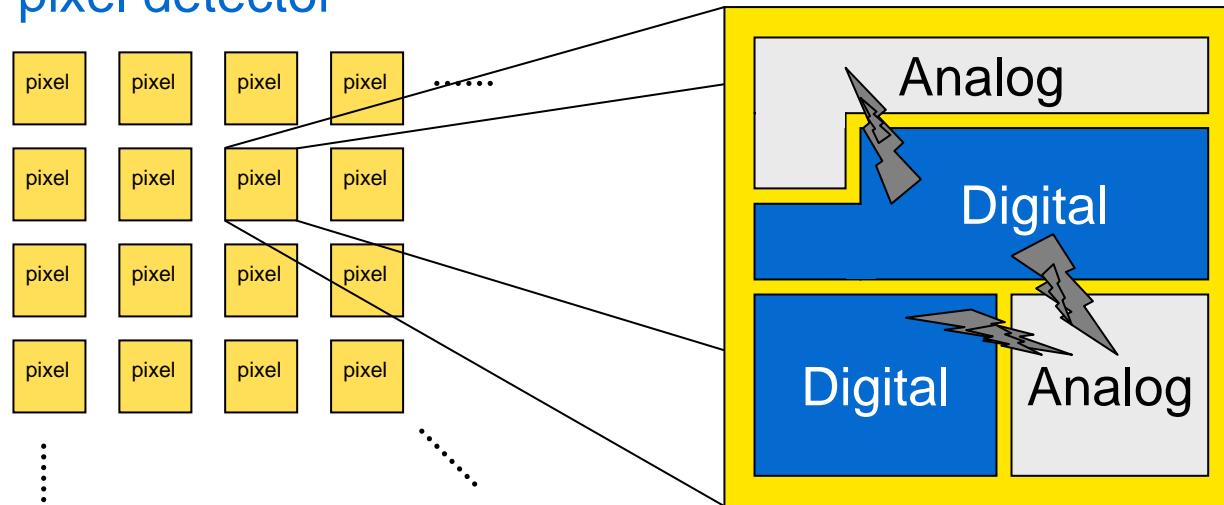
The problem of digital and analog circuits working together.

Outline

- Motivation
- The error scenario
- Simulation models
- Simulation results
- Conclusions
- Future work

Motivation

Photon counting pixel detector



The error scenario

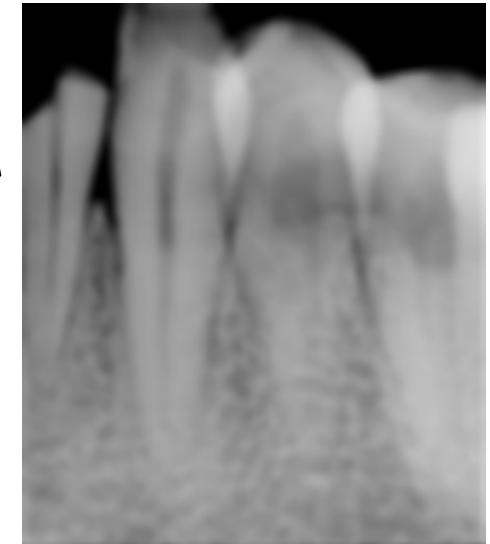
Self-generated
noise within a pixel



Noise between
adjacent pixels

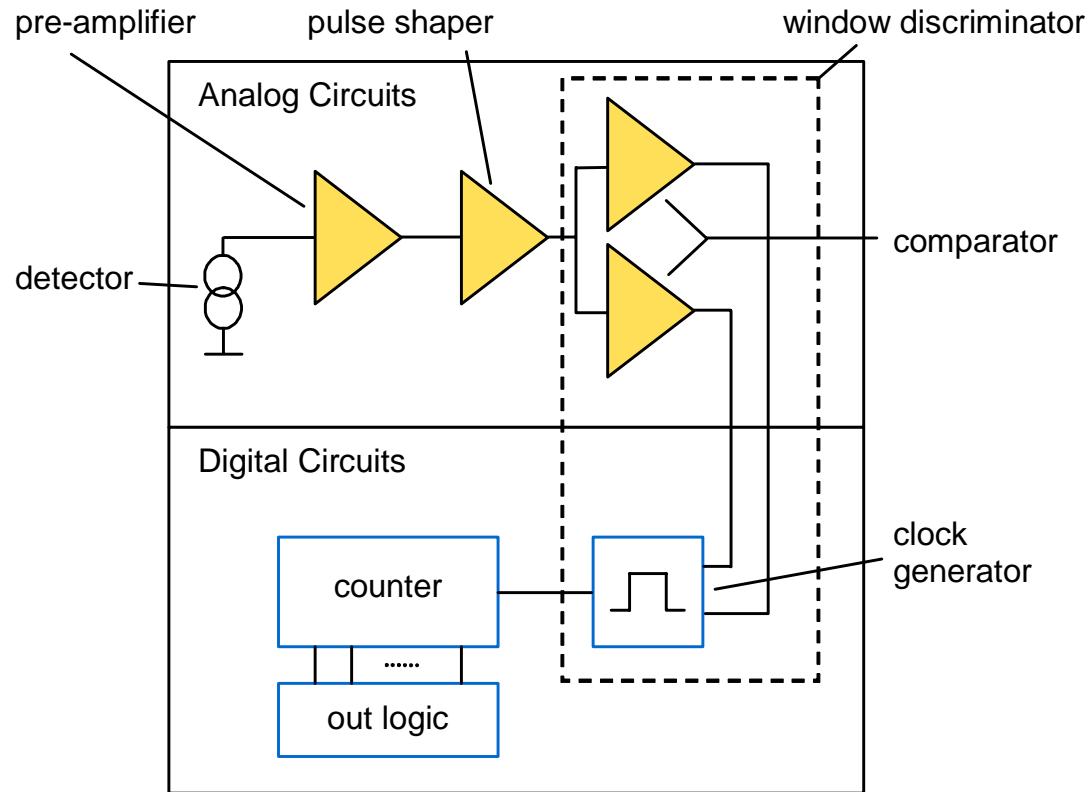


Example of a dental
X-ray image



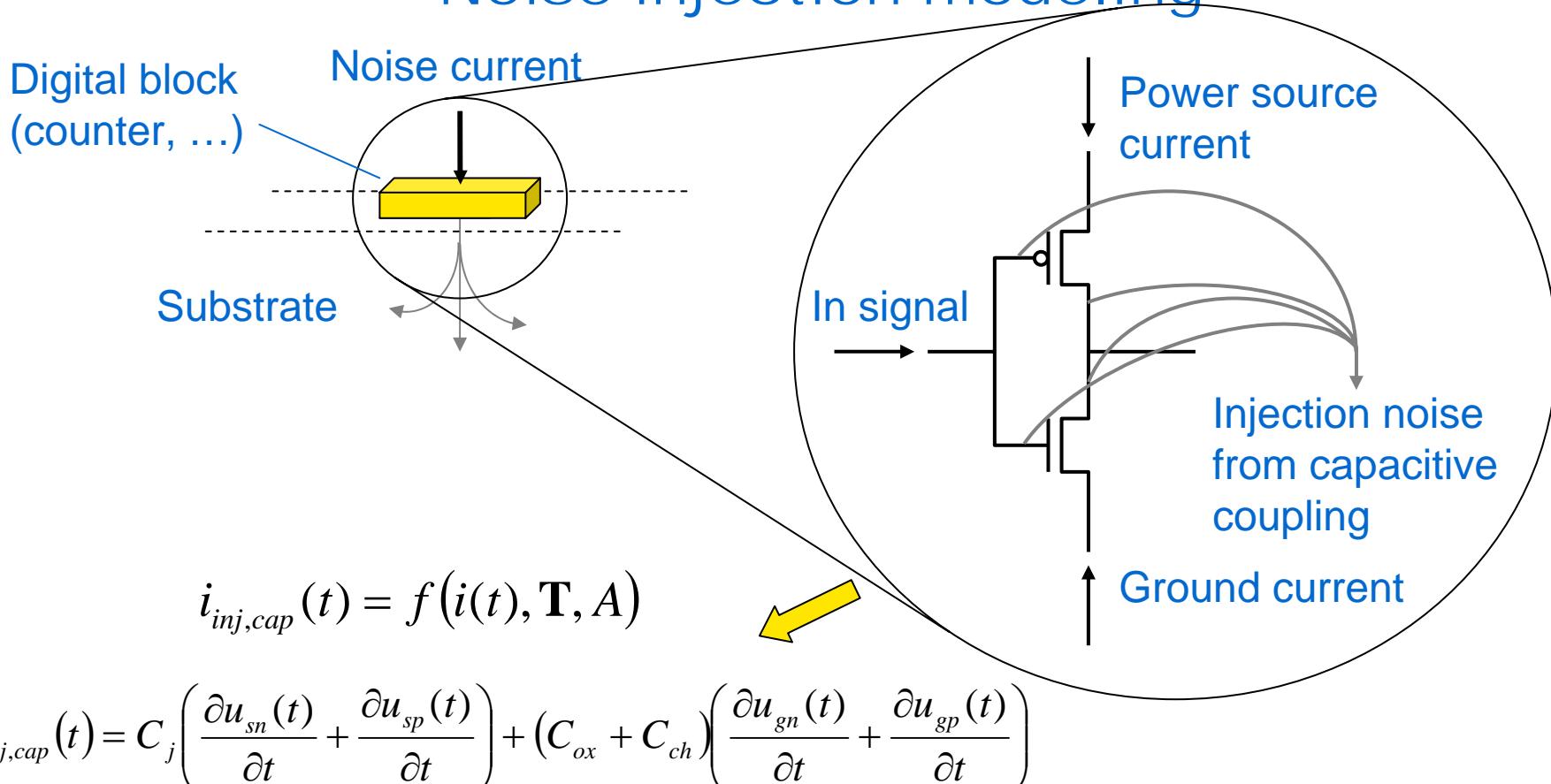
Simulation models

Photon counting pixel detector



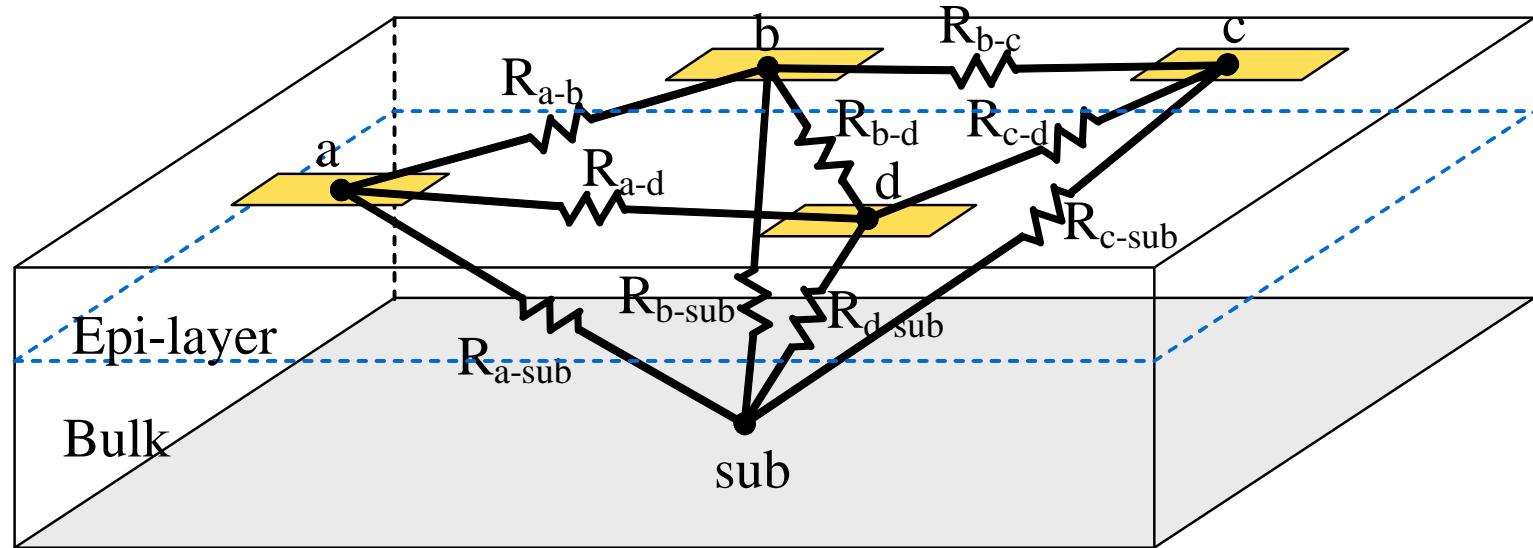
Simulation models

Noise injection modeling



Simulation models

Substrate modeling

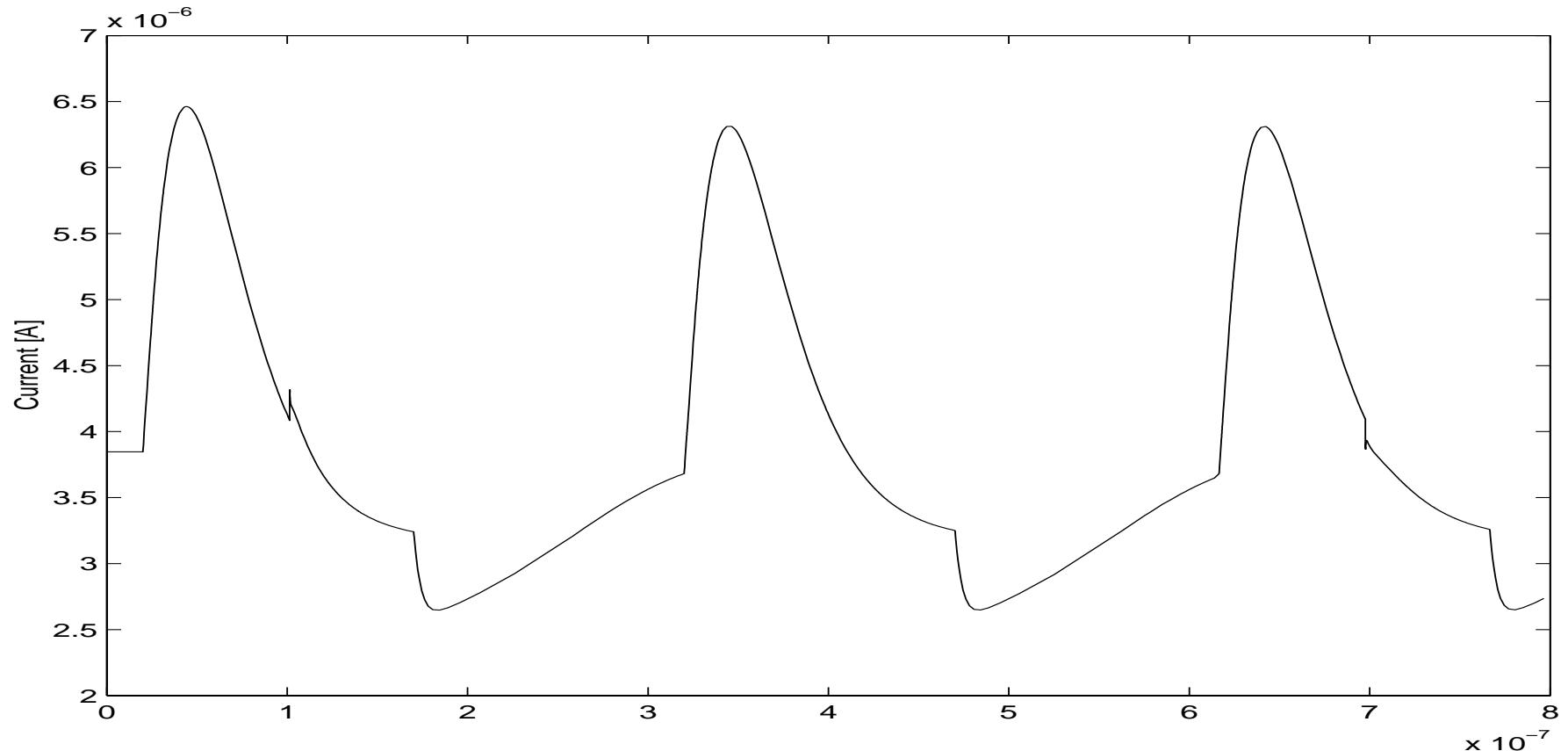


The 3D single substrate node model with
a resistive network ready for simulation.

In this case, with an epi-layer model.

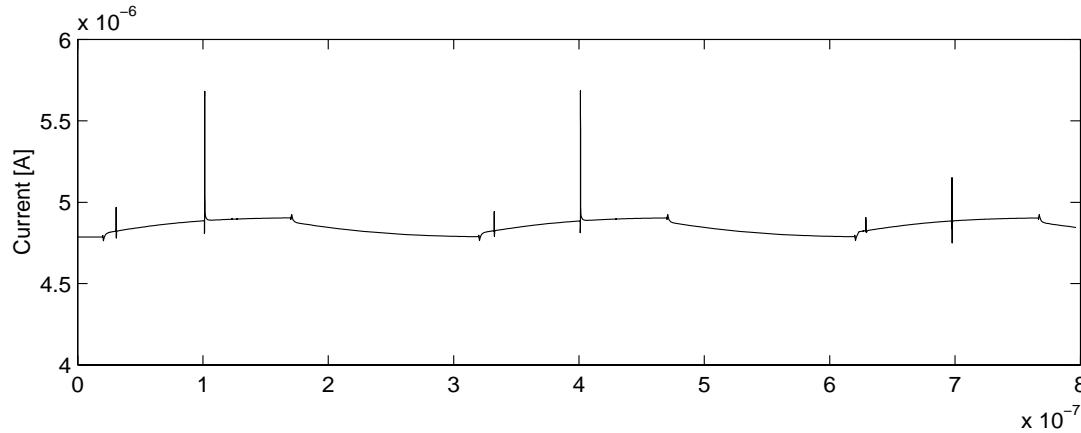
Simulation results

Effect from one bit (20um away)

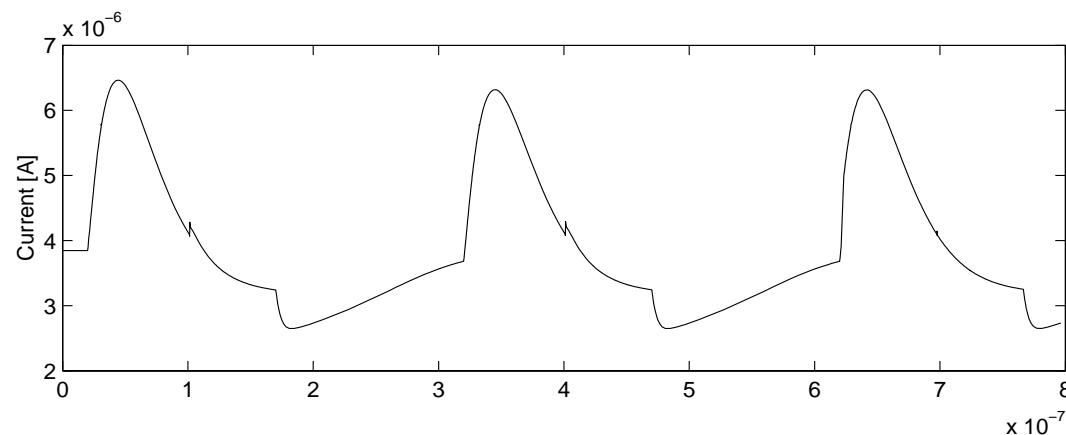


Simulation results

Effect from 12 bits in 12 bit counter (20um)



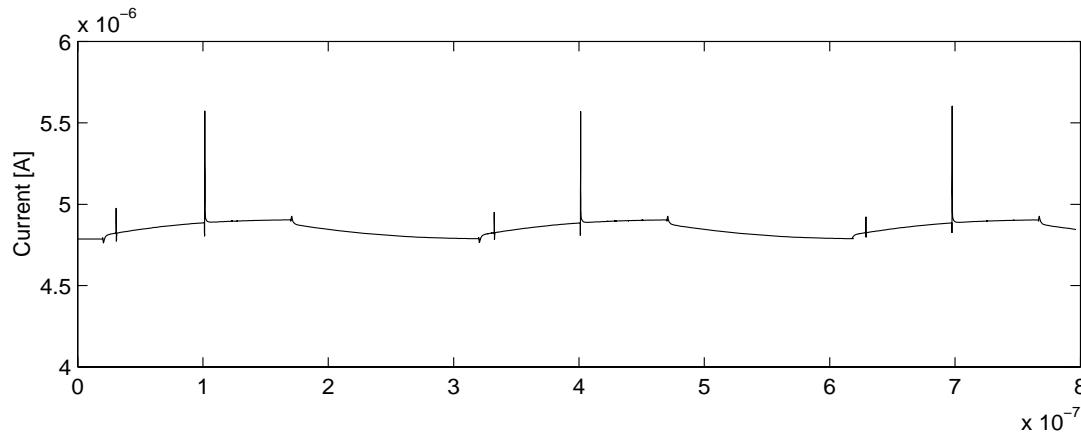
Output current from
preamplifier



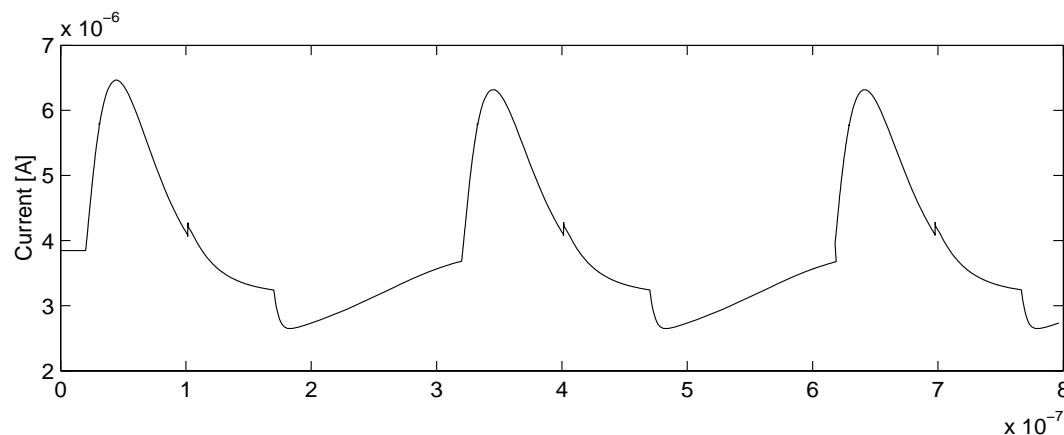
Output current from
pulse shaper

Simulation results

Noise from 16 bits in 16 bit counter (20um)



Output current from
preamplifier



Output current from
pulse shaper

Conclusions

- Substrate coupling needs to be considered in future readout electronics where components are more tightly integrated.
- The problems with substrate noise coupling can be avoided with smart floorplanning.

Future work

- Implementation of remaining parts into Behavioral level Noise Coupling (BeNoC) simulation.
- Behavioral level Noise Coupling (BeNoC) evaluation of photon counting pixel detector.
- Survey and design of RFID sensor interface.